Device simulation Lab: Assignment 5

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EE22M308

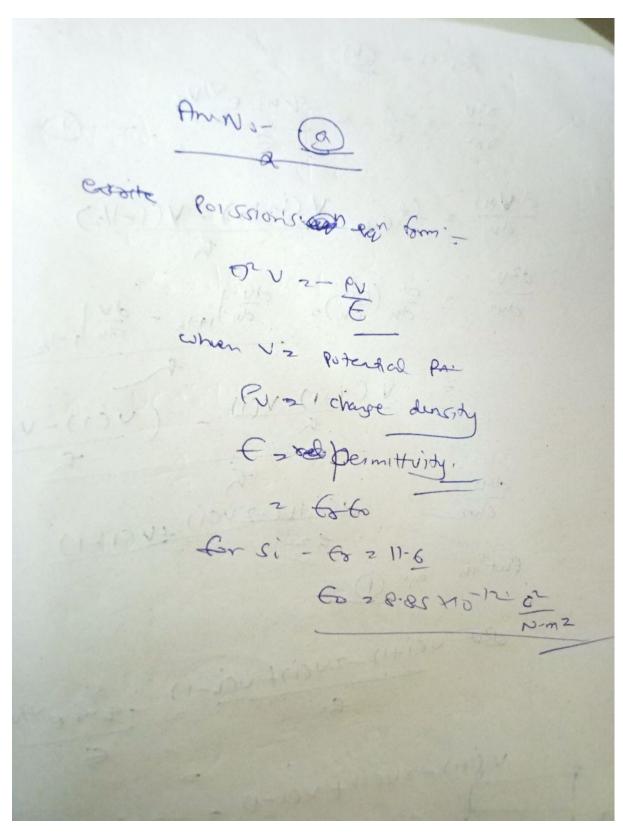
Lab No:5

Software: Matlab 2022a

Numerical solution of Poisson's equation with Maxwell-Boltzmann distribution of carrier density:

Qa. Assuming electrons as the only type of carriers and an undoped semiconductor, write the appropriate form of poisson's equation for electrostatics (assume that the current is zero, and Maxwell-Boltzmann statistics for carriers).

Ans:



Qb. Discretize the above equation such that finite difference method could be used to

solve the same.

ANS:

Anova (1) 3" · E - 3" · O'V. dvan = la ano vicinia) - v(i-1/2) den : du (du) - du little - du l 2 V (141)-V(i) - (V(i)-V(i-0) dro = v(i+1) = v(i) +v(i-1) Put in agn (1) 20 v(i+1) -2v(i)+v(i-1) -2nie√hr V (1+1) - 2 UCi) + UCi-1) = - kenie VIVthe two and parts ASB VA21, 4820 for as points 411- Up 20 122 U(3) + V(1)-2V(2) - Qn/82 (V(2)) V+ =0 123 U(4) + V(2) - 2 V(3) - aniga e V(3) / V7 20 UN - VB 20

Qc. List out the general form for Jacobian for the above set of equations	> .
ANS:	

les for any NEW tapen ponts. fa (v., v2 - - vn) =0 for Previous gets questions equ 5 2 [1 0 0 -- 0 [-2-hancoly - 0 Eut -2-hancoly - 0 Eut -2-hancoly - 0 Eut -0 -- 1 Q d. Consider a semiconductor (say, Silicon) of thickness 200 □m. Assume that one end (A) is

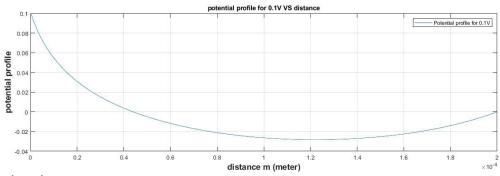
held at at 100mV while the other (B) is held at zero potential. Using a-c given above, solve for

this system using Newton's method. Use a linearly varying potential profile as the initial guess.

Plot the potential and carrier density profiles.

```
ANS:
Code:
Potential:
clear all;
clc;
q=1.6*(10)^{(-19)};
epsilon=103.368*(10)^(-12);
a=200*10^{(-6)};
ni=1.5*(10)^{(16)};
e = 0.0001:
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000:
Va=0.1;
Vb=0;
V=linspace(Va,Vb,1000);
V1=V':
for i=1:1000
F(1,1)=0:
F(1000,1)=0;
for i=2:999
  F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));
end
M(1,1)=1;
for i=2:1000
  M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
end
for i=2:999
  M(i,i+1)=1;
end
for i=1:998
  M(i+1,i)=1;
```

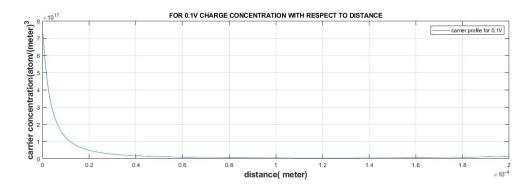
```
end
M(N,N)=1;
p1=inv(M);
p2=p1*F;
V2=V1-p2;
% if abs(V2-V1)<Vt
%
       break:
% end
V1=V2;
end
i=1:1000;
x=i^*(a/1000);
plot(x,V2);
xlabel('distance (meter)');
ylabel('potential profile(volt)');
title('FOR 0.1V POTENTIAL PROFILE WITH RESPECT TO DISTANCE');
grid on;
```



```
Carrier density:
clear all;
clc;
q=1.6*(10)^(-19);
epsilon=103.368*(10)^(-12);
a=200*10^(-6);
ni=1.5*(10)^{(16)};
e = 0.0001;
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000;
Va=0.1;
Vb=0;
V=linspace(Va,Vb,1000);
V1=V';
for i=1:1000
F(1,1)=0;
F(1000,1)=0;
for i=2:999
```

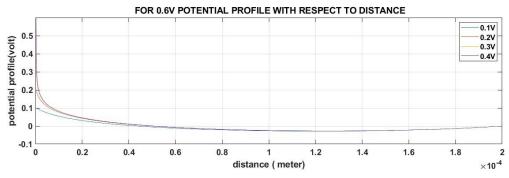
```
end
M(1,1)=1;
for i=2:1000
  M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
end
for i=2:999
  M(i,i+1)=1;
end
for i=1:998
  M(i+1,i)=1;
end
M(N,N)=1;
p1=inv(M);
p2=p1*F;
V2=V1-p2;
% if abs(V2-V1)<Vt
%
       break;
% end
V1=V2;
end
for i=1:1000
  n=ni*exp(V2/Vt);
end
i=1:1000;
x=i*(a/1000);
plot(x,n);
xlabel('distance( meter)');
ylabel('carrier concentration(atom/(meter)^3');
title('FOR 0.1V CHARGE CONCENTRATION WITH RESPECT TO DISTANCE');
grid on;
```

F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));



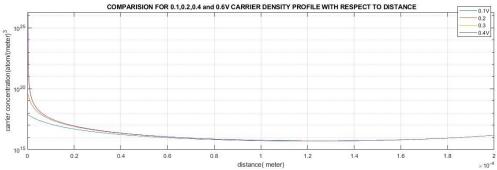
```
Qe. Repeat (d) for applied biases like 200mV, 400mV, and 600mV. Analyse your
solutions.
ANS:
CODE:
Compare:
Potential:
clear all;
clc;
q=1.6*(10)^{(-19)};
epsilon=103.368*(10)^(-12);
a=200*10^{(-6)};
ni=1.5*(10)^{(16)};
e = 0.0001;
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000;
for i=1:4
m=([0.1,0.2,0.4,0.6]);
Va = m(i);
Vb=0;
V=linspace(Va,Vb,1000);
V1=V';
for i=1:1000
F(1,1)=0;
F(1000,1)=0;
for i=2:999
  F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));
end
M(1,1)=1;
for i=2:1000
  M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
end
for i=2:999
  M(i,i+1)=1;
end
for i=1:998
  M(i+1,i)=1;
end
M(N,N)=1;
p1=inv(M);
p2=p1*F;
```

```
V2=V1-p2;
% if abs(V2-V1)<Vt
%
       break:
% end
V1=V2;
end
i=1:1000;
x=i^*(a/1000);
plot(x, V2);
xlabel('distance ( meter)');
ylabel('potential profile(volt)');
title('FOR 0.6V POTENTIAL PROFILE WITH RESPECT TO DISTANCE');
grid on:
hold on
end
```



```
Carrier density:
clear all;
clc;
q=1.6*(10)^(-19);
epsilon=103.368*(10)^(-12);
a=200*10^{(-6)};
ni=1.5*(10)^{(16)};
e = 0.0001;
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000;
for i=1:4
m=([0.1,0.2,0.4,0.6]);
Va = m(i);
Vb=0;
V=linspace(Va, Vb, 1000);
V1=V';
for i=1:1000
F(1,1)=0;
F(1000,1)=0;
for i=2:999
    F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));
```

```
M(1,1)=1;
for i=2:1000
    M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
end
for i=2:999
    M(i,i+1)=1;
end
for i=1:998
    M(i+1,i)=1;
end
M(N,N)=1;
p1=inv(M);
p2=p1*F;
V2=V1-p2;
% if abs(V2-V1)<Vt
          break;
% end
V1=V2;
end
for i=1:1000
    n=ni*exp(V2/Vt);
i=1:1000;
x=i*(a/1000);
plot(x,n);
xlabel('distance( meter)');
ylabel('carrier concentration(atom/(meter)^3');
title(' COMPARISION FOR 0.1,0.2,0.4 and 0.6V CARRIER DENSITY PROFILE WITH RESPECT
TO DISTANCE');
grid on;
hold on
end
```



Qf. Assume that SiO2 of thickness 20nm is deposited at the end A and the potential is applied

across the SiO2 and the Semiconductor. Modify your code in (d) and find the carrier density

profiles inside the semiconductor for an applied bias of 1V. Comment on your results.

```
ANS:
CODE
clear all;
```

clc;

 $q=1.6*(10)^{(-19)}$;

```
epsilon=103.368*(10)^(-12);
a=((200*10^{(-6)})-(20*10^{(-9)}));
ni=1.5*(10)^{(16)};
e = 0.0001;
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000;
Va=1;
Vb=0:
V=logspace(Va,Vb,1000);
V1=V';
for i=1:1000
F(1,1)=0;
F(1000,1)=0;
for i=2:999
  F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));
end
M(1,1)=1;
for i=2:1000
  M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
end
for i=2:999
  M(i,i+1)=1;
end
for i=1:998
  M(i+1,i)=1;
end
M(N,N)=1;
p1=inv(M);
p2=p1*F;
V2=V1-p2;
% if abs(V2-V1)<Vt
%
       break;
% end
V1=V2;
end
for i=1:1000
  n=ni*exp(V2/Vt);
end
i=1:1000;
x=i^*(a/1000);
plot(x,n);
xlabel('distance( meter)');
ylabel('carrier concentration(atom/(meter)^3');
```

title('FOR 1V CHARGE CONCENTRATION WITH RESPECT TO DISTANCE'); grid on;

